

Titles of Most Frequently Occurring Classifications of Patents Returned  
From A Search of 10630537 on November 16, 2005

- 26 714/726 (19 OR, 7 XR)  
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
                   DETECTION/RECOVERY  
       714/699       PULSE OR DATA ERROR HANDLING  
       714/724       .Digital logic testing  
       714/726       ..Scan path testing (e.g., level sensitive scan  
                       design (LSSD))
- 12 714/727 (6 OR, 6 XR)  
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
                   DETECTION/RECOVERY  
       714/699       PULSE OR DATA ERROR HANDLING  
       714/724       .Digital logic testing  
       714/726       ..Scan path testing (e.g., level sensitive scan  
                       design (LSSD))  
       714/727       ...Boundary scan
- 10 714/30 (7 OR, 3 XR)  
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
                   DETECTION/RECOVERY  
       714/100       DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING  
       714/1         .Reliability and availability  
       714/25        ..Fault locating (i.e., diagnosis or testing)  
       714/27        ...Particular access structure  
       714/30        ....Built-in hardware for diagnosing or testing  
                       within-system component (e.g., microprocessor test mode  
                       circuit, scan path)
- 6 714/724 (3 OR, 3 XR)  
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
                   DETECTION/RECOVERY  
       714/699       PULSE OR DATA ERROR HANDLING  
       714/724       .Digital logic testing
- 6 714/729 (1 OR, 5 XR)  
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
                   DETECTION/RECOVERY  
       714/699       PULSE OR DATA ERROR HANDLING  
       714/724       .Digital logic testing  
       714/726       ..Scan path testing (e.g., level sensitive scan  
                       design (LSSD))  
       714/729       ...Plural scan paths
- 5 324/158.1 (1 OR, 4 XR)  
 Class 324 : ELECTRICITY: MEASURING AND TESTING  
       324/158.1    MISCELLANEOUS
- 5 365/201 (0 OR, 5 XR)  
 Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL  
       365/189.01    READ/WRITE CIRCUIT  
       365/201        .Testing
- 5 714/733 (0 OR, 5 XR)  
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
                   DETECTION/RECOVERY  
       714/699       PULSE OR DATA ERROR HANDLING  
       714/724       .Digital logic testing

- 714/733 ..Built-in testing circuit (BILBO)
- 4 714/731 (2 OR, 2 XR)  
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
 DETECTION/RECOVERY  
 714/699 PULSE OR DATA ERROR HANDLING  
 714/724 .Digital logic testing  
 714/726 ..Scan path testing (e.g., level sensitive scan  
 design (LSSD))  
 714/731 ...Clock or synchronization
- 4 716/4 (0 OR, 4 XR)  
 Class 716 : DATA PROCESSING: DESIGN AND ANALYSIS OF  
 CIRCUIT OR SEMICONDUCTOR MASK  
 716/1 CIRCUIT DESIGN  
 716/4 .Testing or evaluating
- 3 324/73.1 (0 OR, 3 XR)  
 Class 324 : ELECTRICITY: MEASURING AND TESTING  
 324/73.1 PLURAL, AUTOMATICALLY SEQUENTIAL TESTS
- 3 714/732 (1 OR, 2 XR)  
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
 DETECTION/RECOVERY  
 714/699 PULSE OR DATA ERROR HANDLING  
 714/724 .Digital logic testing  
 714/732 ..Signature analysis
- 2 714/33 (1 OR, 1 XR)  
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
 DETECTION/RECOVERY  
 714/100 DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING  
 714/1 .Reliability and availability  
 714/25 ..Fault locating (i.e., diagnosis or testing)  
 714/32 ...Particular stimulus creation  
 714/33 ....Derived from analysis (e.g., of a  
 specification or by stimulation)
- 2 714/718 (2 OR, 0 XR)  
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
 DETECTION/RECOVERY  
 714/699 PULSE OR DATA ERROR HANDLING  
 714/718 .Memory testing
- 2 714/725 (0 OR, 2 XR)  
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
 DETECTION/RECOVERY  
 714/699 PULSE OR DATA ERROR HANDLING  
 714/724 .Digital logic testing  
 714/725 ..Programmable logic array (PLA) testing
- 2 714/734 (0 OR, 2 XR)  
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
 DETECTION/RECOVERY  
 714/699 PULSE OR DATA ERROR HANDLING  
 714/724 .Digital logic testing  
 714/734 ..Structural (in-circuit test)
- 2 714/736 (0 OR, 2 XR)  
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
 DETECTION/RECOVERY

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714/699 PULSE OR DATA ERROR HANDLING  
714/724 .Digital logic testing  
714/736 ..Device response compared to expected  
          fault-free response